Notice of References Cited Application/Control No. 10/717,421 Examiner James M. Mitchell Applicant(s)/Patent Under Reexamination BOON ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0080398	05-2003	Badehi, Avner	257/678
	В	US-6,876,061	04-2005	Zandman et al.	257/620
	O	US-2003/0134453	07-2003	Prabhu et al.	438/113
	D	US-2004/0251525	12-2004	Zilber et al.	257/678
	ш	US-6,552,426	04-2003	Ishio et al.	257/692
	F	US-6,379,999	04-2002	Tanabe, Shinji	438/113
	G	US-6,710,454	03-2004	Boon, Suan Jeung	257/777
	H	US-2004/0140573	07-2004	Pu et al.	257/782
	1	US-6,841,418	01-2005	Jeung et al.	438/108
	٦	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

	Document Number Date					1
*		Country Code-Number-Kind Code	MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	x						

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